Search Notes				

T	Application/Control No.	Applicant(s)/Patent under Reexamination
	09/216,378	CHAN ET AL.
	Examiner	Art Unit
	Lun-See Lao	2644

	SEAR	CHED	
Class	Subclass	Date	Examiner
18E	71.1-	7/25/05	L:15.
	71.9		
	71.11-		
	71.13		
	94.7		
	94,1		!

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	1		

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
		<b>:</b>
· · · · · · · · · · · · · · · · · · ·		
		•
		i
•		